

SM3320NSQA-VB Datasheet N-Channel 30-V (D-S) MOSFET

V _{DS}	30	V
R _{DS(on),typ} V _{GS} =10V	13	mΩ
RDS(on),typ VGS=4.5V	19	mΩ
ID	30	Α

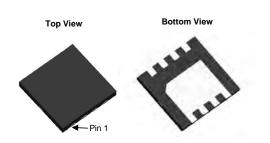
FEATURES

- · Halogen-free
- Trench Power MOSFET
- 100 % R_g and UIS Tested

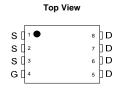


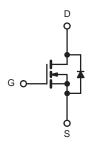
APPLICATIONS

- DC/DC Conversion
 - Low-Side Switch
- Notebook PC
- Gaming



DFN 3x3 EP





N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V_{DS}	30	V	
Gate-Source Voltage		V_{GS}	± 20	V	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C		30		
	$T_C = 70 ^{\circ}\text{C}$ $T_A = 25 ^{\circ}\text{C}$	I _D	20 21.5 ^{b, c}		
	T _A = 70 °C		17.1 ^{b, c}	A	
Pulsed Drain Current		I _{DM}	100		
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	13		
Single Pulse Avalanche Current	T _A = 25 °C	I _{AS}	3.1 ^{b, c} 10		
Avalanche Energy	L = 0.1 mH	E _{AS}	5	mJ	
	T _C = 25 °C		60		
Maximum Power Dissipation	T _C = 70 °C	P _D	30	w	
	T _A = 25 °C		3.7 ^{b, c}		
	T _A = 70 °C		2.4 ^{b, c}		
Operating Junction and Storage Temperature	e Range	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 s	R _{thJA}	27	34	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	6	7.5	C/ VV	

Notes:

- a. Based on $T_C = 25$ °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under Steady State conditions is 85 °C/W.



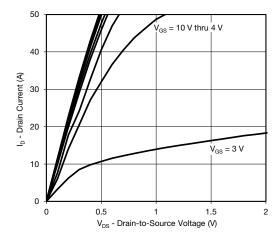
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250A		27		m\//°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	- I _D = 250 μA		- 5.6		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	1.0		3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zone Cote Valta de Brain Comment	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V			1		
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
	В	V _{GS} = 10 V, I _D = 15 A		13		mΩ	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 10 A		19			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 15 A		75		S	
Dynamic ^b							
Input Capacitance	C _{iss}				900	pF	
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz			236		
Reverse Transfer Capacitance	C _{rss}	1			20		
Total Cata Chausa	V ₂₀ = 15 V V ₀₀	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 10 A			20	200	
Total Gate Charge	Q_g				9		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$			2.1	nC	
Gate-Drain Charge	Q _{gd}	1			0.7		
Gate Resistance	R _g	f = 1 MHz	0.2	1.1	2.2	Ω	
Turn-On Delay Time	t _{d(on)}			8	16		
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		16	30		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		17	35		
Fall Time	t _f			7	15		
Turn-On Delay Time	t _{d(on)}			14	30	ns	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, R_{L} = 1.5 \Omega$		50	100	- - -	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		16	30		
Fall Time	t _f	1		8	18		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			13	^	
Pulse Diode Forward Current ^a	I _{SM}				100	А	
Body Diode Voltage	V _{SD}	I _S = 3 A			1.2	V	
Body Diode Reverse Recovery Time	t _{rr}				40	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 10 A, dl/dt = 100 A/μs, T _J = 25 °C			20	nC	
Reverse Recovery Fall Time	t _a	- 1 _F = 10 A, αί/αι = 100 A/μs, 1 _J = 25 °C		12.5			
Reverse Recovery Rise Time	t _b			7.5		ns	

Notes:

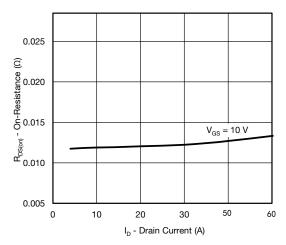
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$ b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

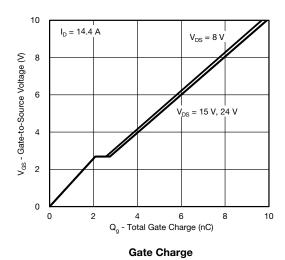


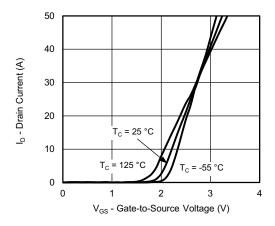


Output Characteristics

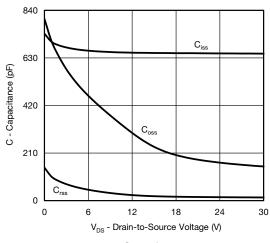


On-Resistance vs. Drain Current

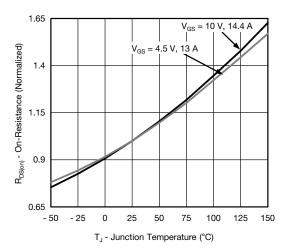




Transfer Characteristics

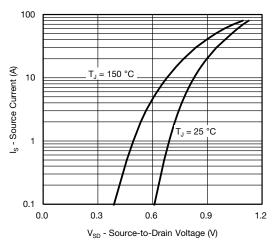


Capacitance

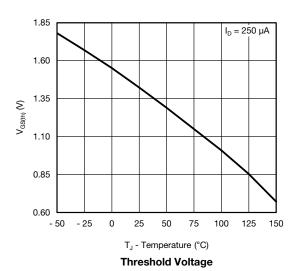


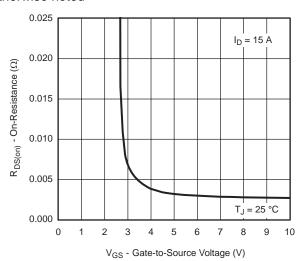
On-Resistance vs. Junction Temperature



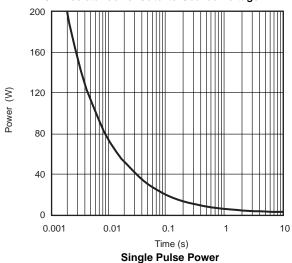


Source-Drain Diode Forward Voltage





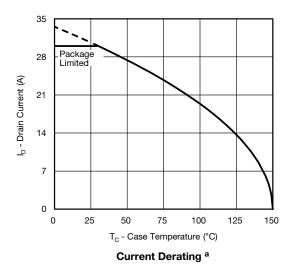
On-Resistance vs. Gate-to-Source Voltage

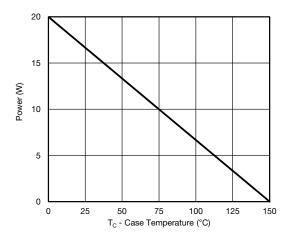


 $(3) \begin{array}{c} 100 \\ \text{Limited by } P_{\text{Oscion}} \\ 10 \\ \text{Limited by } P_{\text{Oscion}} \\ 1 \\ \text{O.01} \\ \text{O.1} \\ \text{O.1} \\ \text{O.1} \\ \text{O.1} \\ \text{O.2} \\ \text{O.2} \\ \text{O.3} \\ \text{O.3} \\ \text{O.4} \\ \text{O.5} \\ \text{O.7} \\ \text{O.8} \\ \text{O.8} \\ \text{O.9} \\ \text{O.$

Safe Operating Area, Junction-to-Ambient





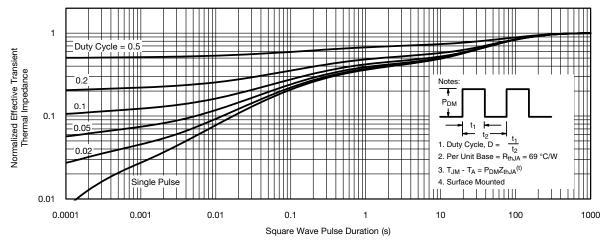


Power, Junction-to-Case

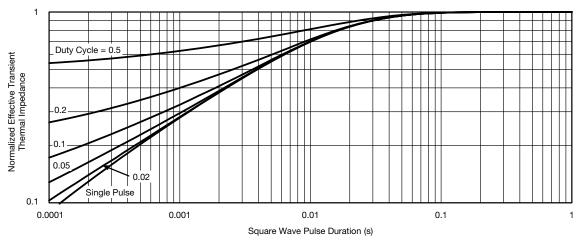
Note

a. The power dissipation P_D is based on T_J max. = 25 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



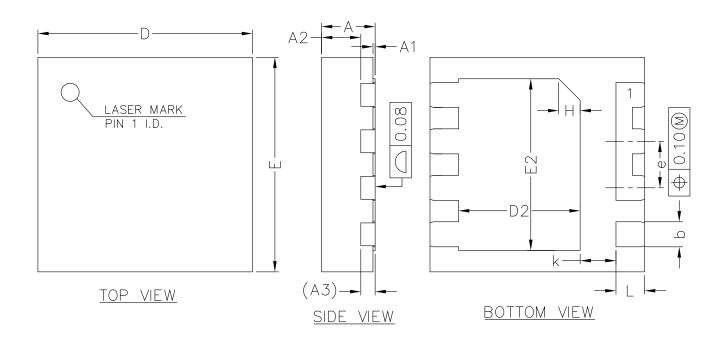


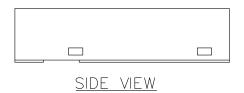
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case







COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
А	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
А3	0.20REF			
Ь	0.30	0.35	0.40	
D	2.90	3.00	3.10	
E	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
K	0.40	0.50	0.60	
L	0.35	0.40	0.45	



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